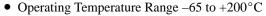


# **SWITCHMODE™ Series NPN Silicon Power Transistors**

The BUS98 and BUS98A transistors are designed for high-voltage, high-speed, power switching in inductive circuits where fall time is critical. They are particularly suited for line-operated SWITCHMODE applications such as:

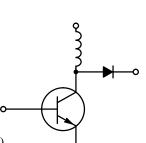
- Switching Regulators
- Inverters
- Solenoid and Relay Drivers
- Motor Controls
- Deflection Circuits
- Fast Turn-Off Times

60 ns Inductive Fall Time –25°C (Typ) 120 ns Inductive Crossover Time –25°C (Typ)



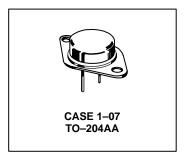
• 100°C Performance Specified for:

Reverse–Biased SOA with Inductive Loads Switching Times with Inductive Loads Saturation Voltages Leakage Currents (125°C)



## BUS98 BUS98A

30 AMPERES
NPN SILICON
POWER TRANSISTORS
400 AND 450 VOLTS
(BVCEO)
250 WATTS
850-1000 V (BVCES)



#### **MAXIMUM RATINGS**

Rating	Symbol	BUS98	BUS98A	Unit
Collector–Emitter Voltage	V <sub>CEO(sus)</sub>	400	450	Vdc
Collector–Emitter Voltage	V <sub>CEV</sub>	850	1000	Vdc
Emitter Base Voltage	V <sub>EB</sub>	7		Vdc
Collector Current — Continuous — Peak (1) — Overload	Ic I <sub>CM</sub> I <sub>ol</sub>	30 60 120		Adc
Base Current — Continuous — Peak (1)	I <sub>B</sub>	10 30		Adc
Total Power Dissipation — T <sub>C</sub> = 25°C — T <sub>C</sub> = 100°C Derate above 25°C	P <sub>D</sub>	250 142 1.42		Watts W/°C
Operating and Storage Junction Temperature Range	0 0, 0,9		to +200	°C

#### THERMAL CHARACTERISTICS

Characteristic	Symbol	Max	Unit
Thermal Resistance, Junction to Case	R <sub>θJC</sub>	0.7	°C/W
Maximum Lead Temperature for Soldering Purposes: 1/8" from Case for 5 Seconds	TL	275	°C

<sup>(1)</sup> Pulse Test: Pulse Width = 5 ms, Duty Cycle ≦10%. Designer's and SWITCHMODE are trademarks of ON Semiconductor, Inc.

#### **ELECTRICAL CHARACTERISTICS** (T<sub>C</sub> = 25°C unless otherwise noted)

Characteristic	Symbol	Min	Тур	Max	Unit	
OFF CHARACTERISTICS (1)						
Collector–Emitter Sustaining Voltage (Table 1) $(I_C = 200 \text{ mA}, I_B = 0) \text{ L} = 25 \text{ mH}$	BUS98 BUS98A	V <sub>CEO(sus)</sub>	400 450		_	Vdc
Collector Cutoff Current $(V_{CEV} = Rated \ Value, \ V_{BE(off)} = 1.5 \ Vdc)$ $(V_{CEV} = Rated \ Value, \ V_{BE(off)} = 1.5 \ Vdc, \ T_C = 125 ^{\circ}C)$		I <sub>CEV</sub>		_	0.4 4.0	mAdc
Collector Cutoff Current ( $V_{CE}$ = Rated $V_{CEV}$ , $R_{BE}$ = 10 $\Omega$ )	T <sub>C</sub> = 25 °C T <sub>C</sub> = 125 °C	I <sub>CER</sub>	<u> </u>	_ _	1.0 6.0	mAdc
Emitter Cutoff Current $(V_{EB} = 7 \text{ Vdc}, I_C = 0)$		I <sub>EBO</sub>	_	_	0.2	mAdc
Emitter–Base Breakdown Voltage $(I_E = 100 \text{ mA} - I_C = 0)$		V <sub>EBO</sub>	7.0	_	_	Vdc
SECOND BREAKDOWN						1
Second Breakdown Collector Current with Base Forward	d Biased	I <sub>S/b</sub>		See Fig	gure 12	
Clamped Inductive SOA with Base Reverse Biased		RBSOA		See Fig	gure 13	
ON CHARACTERISTICS (1)						
DC Current Gain ( $I_C = 20$ Adc, $V_{CE} = 5$ Vdc) ( $I_C = 16$ Adc, $V_{CE} = 5$ V)	BUS98 BUS98A	h <sub>FE</sub>	8	_	_	_
Collector–Emitter Saturation Voltage ( $I_C$ = 20 Adc, $I_B$ = 4 Adc) ( $I_C$ = 30 Adc, $I_B$ = 8 Adc) ( $I_C$ = 20 Adc, $I_B$ = 4 Adc, $T_C$ = 100°C) ( $I_C$ = 16 Adc, $I_B$ = 3.2 Adc) ( $I_C$ = 24 Adc, $I_B$ = 5 Adc) ( $I_C$ = 16 Adc, $I_B$ = 3.2 Adc, $I_C$ = 100°C)	BUS98 BUS98A	V <sub>CE(sat)</sub>		_ _ _ _ _	1.5 3.5 2.0 1.5 5.0 2.0	Vdc
Base–Emitter Saturation Voltage ( $I_C$ = 20 Adc, $I_B$ = 4 Adc) ( $I_C$ = 20 Adc, $I_B$ = 4 Adc, $T_C$ = 100°C) ( $I_C$ = 16 Adc, $I_B$ = 3.2 Adc) ( $I_C$ = 16 Adc, $I_B$ = 3.2 Adc, $T_C$ = 100°C)	BUS98 BUS98A	V <sub>BE(sat)</sub>	_ _ _ _	_ _ _ _	1.6 1.6 1.6 1.6	Vdc
DYNAMIC CHARACTERISTICS		_		•	T	
Output Capacitance ( $V_{CB} = 10 \text{ Vdc}$ , $I_E = 0$ , $f_{test} = 100 \text{ kHz}$ )	C <sub>ob</sub>	_	_	700	pF	
SWITCHING CHARACTERISTICS Restive Load (Table 1)						
Delay Time		t <sub>d</sub>	_	0.1	0.2	μs
Rise Time $(V_{CC} = 250 \text{ Vdc}, I_{C} = 2 \text{ I}_{B1} = 4.0 \text{ A}, t_{p} = 30 \mu$		t <sub>r</sub>	_	0.4	0.7	- - -
Storage Time Duty Cycle ≤ 2%, V <sub>BE(off</sub>	) = 5 V)	t <sub>s</sub>	_	1.55	2.3	
	= 3.2 A)	t <sub>f</sub>	_	0.2	0.4	1
Fall Time (for BUS98A: I <sub>C</sub> = 16 A, lb <sub>1</sub>		1		I.	l	1
Fall Time (for BUS98A: I <sub>C</sub> = 16 A, Ib <sub>1</sub>						
Fall Time (for BUS98A: I <sub>C</sub> = 16 A, Ib <sub>1</sub>		t <sub>sv</sub>		1.55	_	μs
Fall Time (for BUS98A: $I_C = 16 \text{ A}$ , $Ib_1$ )  Inductive Load, Clamped (Table 1)  Storage Time $I_{C(pk)} = 20 \text{ A}$ (BUS98)  Fall Time $I_{b1} = 4 \text{ A}$	(T <sub>C</sub> = 25°C)	t <sub>sv</sub>		1.55 0.06	_	μs
Fall Time (for BUS98A: $I_C = 16 \text{ A}$ , $Ib_1$ )  Inductive Load, Clamped (Table 1)  Storage Time $I_{C(pk)} = 20 \text{ A}$ (BUS98) $I_{b1} = 4 \text{ A}$ $I_{b1} = 4 \text{ A}$ $I_{b2} = 4 \text{ A}$ $I_{b2} = 4 \text{ A}$ $I_{b3} = 4 \text{ A}$ $I_{b4} = 4 \text{ A}$ $I_{b5} = 4  $	(T <sub>C</sub> = 25°C)	t <sub>fi</sub>				μѕ
Fall Time (for BUS98A: $I_C = 16 \text{ A}$ , $Ib_1$ )  Inductive Load, Clamped (Table 1)  Storage Time $I_{C(pk)} = 20 \text{ A}$ (BUS98) $I_{b1} = 4 \text{ A}$ $V_{BE(off)} = 5 \text{ V}$ ,	$(T_C = 25^{\circ}C)$ $(T_C = 100^{\circ}C)$			0.06	_	μs

<sup>(1)</sup> Pulse Test: PW = 300  $\mu s$ , Duty Cycle  $\leq$  2%.

#### **DC CHARACTERISTICS**

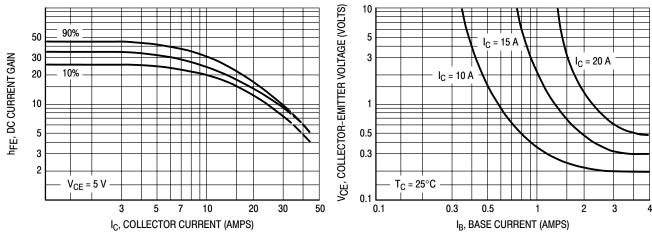


Figure 1. DC Current Gain

Figure 2. Collector Saturation Region

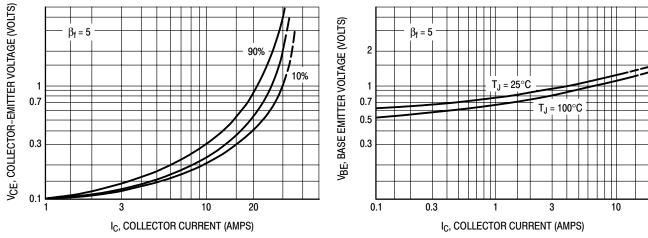


Figure 3. Collector-Emitter Saturation Voltage

Figure 4. Base-Emitter Voltage

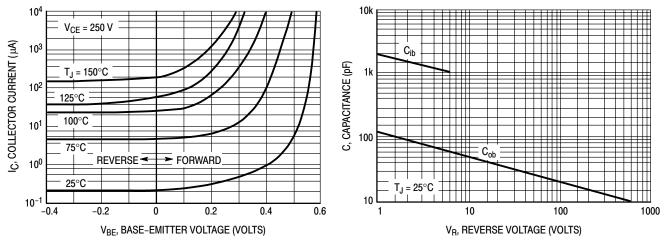
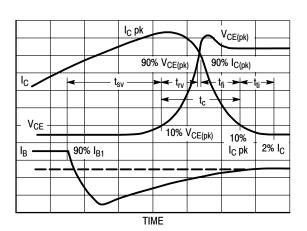


Figure 5. Collector Cutoff Region

Figure 6. Capacitance

**Table 1. Test Conditions for Dynamic Performance** 

	V <sub>CEO(sus)</sub>	RBSOA AND INDUCTIVE SWITCHING	RESISTIVE SWITCHING
INPUT	+10 V $\rightarrow$ 20 1 0 1 $\rightarrow$ 2 2 $=$ PW Varied to Attain $I_C = 100 \text{ mA}$	HJE200  BUV20  MJE210  BUV20  MJE210  ADJUST V <sub>C2</sub> TO OBTAIN DESIRED I <sub>B1</sub> ADJUST V <sub>C2</sub> TO OBTAIN DESIRED I <sub>B2</sub>	TURN-ON TIME  O 1  IB1 = 2  IB1 adjusted to obtain the forced hFE desired  TURN-OFF TIME  Use inductive switching driver as the input to the resistive test circuit.
CIRCUIT	$L_{coil}$ = 25 mH, $V_{CC}$ = 10 V $R_{coil}$ = 0.7 $\Omega$	$\begin{array}{ll} L_{coii} = 180~\mu H \\ R_{coii} = 0.05~\Omega \\ V_{CC} = 20~V \end{array} \qquad \qquad V_{clamp} = 250~V \label{eq:vcc}$	V <sub>CC</sub> = 250 V Pulse Width = 10 μs
TEST CIRCUITS	TUT 1 IN-	TEST CIRCUIT  OUTPUT WAVEFORMS $t_1 \text{ Adjusted to Obtain } l_C$ $t_1 \approx \frac{L_{coil} (lC(pk))}{V_{CC}}$ $t_2 \approx \frac{L_{coil} (lC(pk))}{V_{Clamp}}$ $t_3 \approx \frac{L_{coil} (lC(pk))}{V_{Clamp}}$ $t_4 \approx \frac{L_{coil} (lC(pk))}{V_{Clamp}}$ $t_5 \approx \frac{L_{coil} (lC(pk))}{V_{clamp}}$ Test Equipment Scope — Tektronix 475 or Equivalent	RESISTIVE TEST CIRCUIT  1 O RL 2 O VCC VCC





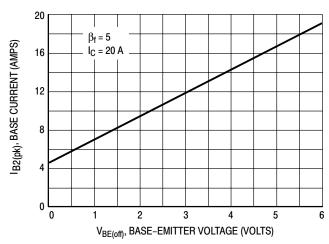


Figure 8. Peak-Reverse Current

#### **SWITCHING TIMES NOTE**

In resistive switching circuits, rise, fall, and storage times have been defined and apply to both current and voltage waveforms since they are in phase. However, for inductive loads which are common to SWITCHMODE power supplies and hammer drivers, current and voltage waveforms are not in phase. Therefore, separate measurements must be made on each waveform to determine the total switching time. For this reason, the following new terms have been defined.

 $t_{sv}$  = Voltage Storage Time, 90%  $I_{B1}$  to 10%  $V_{clamp}$ 

 $t_{rv}$  = Voltage Rise Time, 10–90%  $V_{clamp}$ 

 $t_{fi}$  = Current Fall Time, 90–10%  $I_C$ 

 $t_{ti} = Current Tail, 10-2\% I_C$ 

 $t_c$  = Crossover Time, 10%  $V_{clamp}$  to 10%  $I_C$ 

An enlarged portion of the inductive switching waveforms is shown in Figure 7 to aid in the visual identity

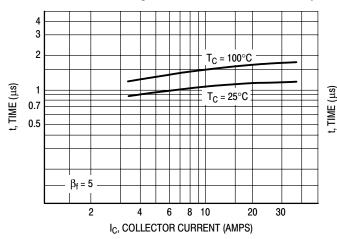


Figure 9. Storage Time, tsv

of these terms

For the designer, there is minimal switching loss during storage time and the predominant switching power losses occur during the crossover interval and can be obtained using the standard equation from AN–222:

$$P_{SWT} = 1/2 V_{CC}I_{C}(t_{c}) f$$

In general,  $t_{rv} + t_{fi} \approx t_c$ . However, at lower test currents this relationship may not be valid.

As is common with most switching transistors, resistive switching is specified at 25°C and has become a benchmark for designers. However, for designers of high frequency converter circuits, the user oriented specifications which make this a "SWITCHMODE" transistor are the inductive switching speeds (t<sub>c</sub> and t<sub>sv</sub>) which are guaranteed at 100°C.INDUCTIVE SWITCHING

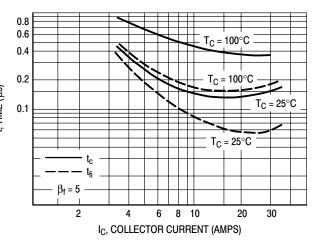


Figure 10. Crossover and Fall Times

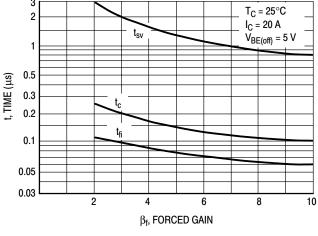


Figure 11. Turn-Off Times versus Forced Gain

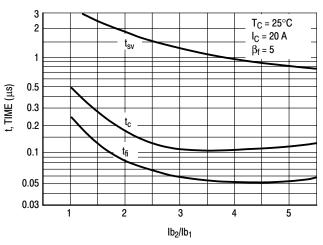


Figure 12. Turn-Off TM Times versus Ib<sub>2</sub>/Ib<sub>1</sub>

The Safe Operating Area figures shown in Figures 12 and 13 are specified for these devices under the test conditions shown.

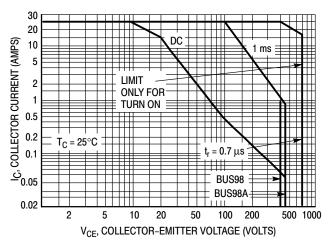


Figure 13. Forward Bias Safe Operating Area

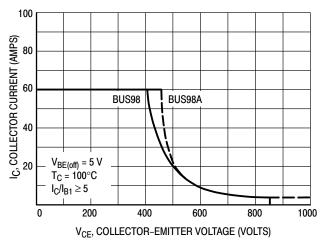


Figure 14. Reverse Bias Safe Operating Area

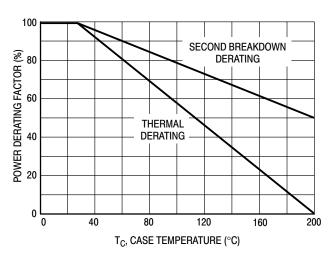


Figure 15. Power Derating

#### SAFE OPERATING AREA INFORMATION

#### **FORWARD BIAS**

There are two limitations on the power handling ability of a transistor: average junction temperature and second breakdown. Safe operating area curves indicate  $I_C - V_{CE}$  limits of the transistor that must be observed for reliable operation, i.e., the transistor must not be subjected to greater dissipation than the curves indicate.

The data of Figure 13 is based on  $T_C = 25^{\circ}C$ ;  $T_{J(pk)}$  is variable depending on power level. Second breakdown pulse limits are valid for duty cycles to 10% but must be derated when  $T_C \ge 25^{\circ}C$ . Second breakdown limitations do not derate the same as thermal limitations. Allowable current at the voltages shown on Figure 13 may be found at any case temperature by using the appropriate curve on Figure 15.

 $T_{J(pk)}$  may be calculated from the data in Figure 11. At high case temperatures, thermal limitations will reduce the power that can be handled to values less than the limitations imposed by second breakdown.

#### **REVERSE BIAS**

For inductive loads, high voltage and high current must be sustained simultaneously during turn-off, in most cases, with the base to emitter junction reverse biased. Under these conditions the collector voltage must be held to a safe level at or below a specific value of collector current. This can be accomplished by several means such as active clamping, RC snubbing, load line shaping, etc. The safe level for these devices is specified as Reverse Bias Safe Operating Area and represents the voltage-current conditions during reverse biased turn-off. This rating is verified under clamped conditions so that the device is never subjected to an avalanche mode. Figure 14 gives RBSOA characteristics.

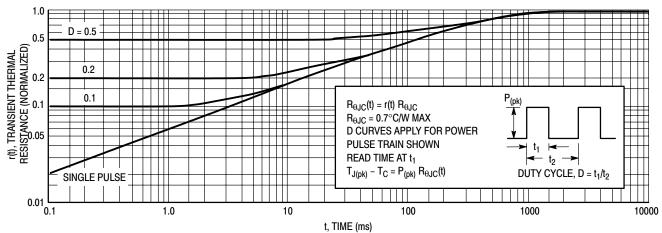


Figure 16. Thermal Response

#### **OVERLOAD CHARACTERISTICS**

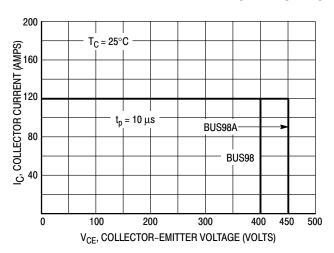


Figure 17. Rated Overload Safe Operating Area (OLSOA)

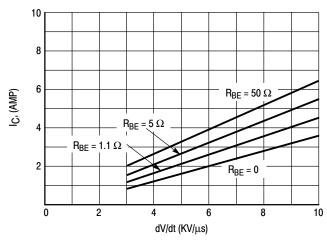


Figure 18. Figure 17.  $I_C = f (dV/dt)$ 

#### **OLSOA**

OLSOA applies when maximum collector current is limited and known. A good example Is a circuit where an inductor is inserted between the transistor and the bus, which limits the rate of rise of collector current to a known value. If the transistor is then turned off within a specified amount of time, the magnitude of collector current is also known.

Maximum allowable collector-emitter voltage versus collector current is plotted for several pulse widths. (Pulse width is defined as the time lag between the fault condition and the removal of base drive.) Storage time of the transistor has been factored into the curve. Therefore, with bus voltage and maximum collector current known, Figure 17 defines the maximum time which can be allowed for fault detection and shutdown of base drive.

OLSOA is measured in a common—base circuit (Figure 19) which allows precise definition of collector—emitter voltage and collector current. This is the same circuit that is used to measure forward—bias safe operating area.

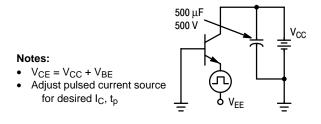
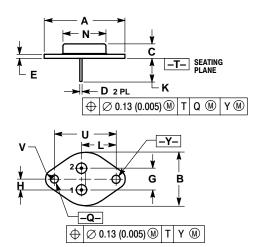


Figure 19. Overload SOA Test Circuit

#### PACKAGE DIMENSIONS

TO-204AA (TO-3) **CASE 1-07 ISSUE Z** 



#### NOTES

- DIMENSIONING AND TOLERANCING PER ANSI
- Y14.5M, 1982. 2. CONTROLLING DIMENSION: INCH.
- ALL RULES AND NOTES ASSOCIATED WITH REFERENCED TO-204AA OUTLINE SHALL APPLY.

	INCHES		MILLIMETERS		
DIM	MIN	MAX	MIN	MAX	
Α	1.550	REF	39.37 REF		
В		1.050		26.67	
С	0.250	0.335	6.35	8.51	
D	0.038	0.043	0.97	1.09	
Ε	0.055	0.070	1.40	1.77	
G	0.430	0.430 BSC 10.92 BSC		BSC	
Н	0.215 BSC		5.46 BSC		
K	0.440	0.480	11.18	12.19	
L	0.665 BSC		16.89 BSC		
N		0.830		21.08	
Q	0.151	0.165	3.84	4.19	
U	1.187	BSC	30.15 BSC		
٧	0.131	0.188	3.33	4.77	

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